ON Semiconductor®



Title of Change:	Bumping process trans	Bumping process transfer from Amkor Taiwan to JCAP China on EA2M-SWC8A1G		
Proposed First Ship date:	01 Jun 2021 or earlier if approved by customer			
Contact Information:	Contact your local ON Semiconductor Sales Office or <u>Jimmy.Zhang@onsemi.com</u>			
PCN Samples Contact:	Contact your local ON Semiconductor Sales Office or < <u>PCN.samples@onsemi.com</u> >. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.			
Additional Reliability Data:	Contact your local ON	Contact your local ON Semiconductor Sales Office or Paul.Syndergaard@onsemi.com		
Type of Notification:	days prior to impleme ON Semiconductor wil	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <u>PCN.Support@onsemi.com</u>		
Marking of Parts/ Traceability of Change:	None	None		
Change Category:	Assembly Change	Assembly Change		
Change Sub-Category(s):	Material Change, Mar	Material Change, Manufacturing Process Change, Manufacturing Site Transfer		
Sites Affected:				
ON Semiconductor Sites		External Foundry/Subcon Sites		
None		AMKOR, Taiwan T5		

Description and Purpose:

Qualify JCAP as a new bumping site to replace Amkor T5 by end of 2020 for EA2M-SWC8A1G. The purpose of the change is to improve the capacity and material flow.

JCAP, China

	Before Change Description	After Change Description
Bumping site	Amkor Taiwan	JCAP china –qualified bumping site for other ON Semiconductor products
RDL design	Linewidth > 60um	Linewidth 55um+/-6um
Bump design	PI2 opening (90um) UBM size (110um +/-3um)	Larger PI2 opening (103um+/-10um) and UBM size (123um) to match the bump height
BOM material	Seed layer material is Tiw/Cu	Use Ti/Cu seed layer
Case outline	Current	Match the existing case outline

There is no product marking change as a result of this change.

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Reliability Data Summary:

QV DEVICE NAME: EA2M-SWC8AIG RMS: S71784

PACKAGE: WLCSP

Test	Specification	Condition	Interval	Results
HTSL	JESD22-A103	Ta= 150°C	504 hrs	0/90
TC	JESD22-A104	Ta= -40°C to +125°C	500 cyc	0/90
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	34 hrs	0/90
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/90
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C		0/123

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Part Number	Qualification Vehicle	
EA2M-SWC8A1G	EA2M-SWC8A1G	